SHEET 1 OF 1

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LISTO	FREFE	RENCES CITED BY AF	PEICANI	Kouji MITSUHAS	HI, et al.				
				FILING DATE	•		GROUP		
				November 28, 20	03		1763		
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EXAMINER INITIAL	1	DOCUMENT NUMBER	DATE	NAM	E	CLASS	CLASS		ROPRIATE
	+	5,952,054	9-14-99	Sato et al.					
RD	AA	5,952,054	5-14-55	Satu et al.					
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RD	AO	1999-008142	1-25-99	Korea (Corresponds			ļ		×
	AP	05-070922	3-23-93	Japan (English Abstrate translation)	act w/partial compi	uterizea			
	1.0	0004 450007	5.54	Japan (English Abstr	act w/partial comp	uterized			
	AQ	2001-152307	6-5-01	translation)					
	AR	10-130884	5-19-98	Japan (English Abstraction)	act w/partial compi	uterized			
<u> </u>	AS	· · · · · · · · · · · · · · · · · · ·		translation)					
		 							
	AT		 				 -		
	AU		<u> </u>				 		
	AV			l					
		OTHER RE	FERENCES (Including Author, Titl	e, Date, Pertinent	Pages, e	tc.)		
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Form PTO 1449		U.S. DEPA	RTMENT OF	ATTY DOCKET NO.	SERIAL	NO.
(Modified)		PATENT	AND TRADEMARK	246070US2	10/722	2,602
OFFICE				APPLICANT		
LIST OF RE	FERE	NCES CITED BY	EPPHEANT	Kouji Mitsuhashi, et al.		
			EIAD	FILING DATE	GROUP	
	_		5000	ស្គីNovember 28, 2003	1763	
		2	14 0 2 2016	POREIGN PATENT DOCUMENTS		
EXAMINER		DOCUMENT, NUMBER	DAIR	COUNTRY		LATION
INITIAL			1-11-		YES	NO
RD	AA	1 156 130	11/21/2001	Europe (in English)	×	
	AB	10-004083	01/06/1998	Japan (w/ English abstract and computer translation)	 ^ 	
	AC	2001-226773	08/21/2001	Japan (w/ English abstract; ∞rresponding to US 2001/0003271 A1)	 	
	AD	2000-303180	10/31/2000	Japan (w/ English abstract; corresponding to US 2003/0010446 A1)		×
	AE	0 814 495	06/1997	Europe (in English)	 	
	AF	05-198532	08/1993	Japan (w/ English abstract and computer translation)	×	
	AG	10-214819	08/1998	Japan (w/ English abstract and computer translation)	×	
	AH	2002-151473	05/2002	Japan (w/ English abstract; corresponding to US 2004/0035364 A1)		×
	Al	02/39495	05/16/2002	WIPO (w/ English abstract; corresponding to US 2004/0035364 A1)	ļ	×
	AJ	1 069 603	01/17/2001	Europe (in English)		
	AK	07-245295	09/1995	Japan (w/ English abstract and computer translation)	×	
	AL	0 841 838	05/1998	Europe (in English)		
	AM	99/50886	10/1999	WIPO (in English)		
	AN	0 573 057	12/1993	Europe (in English)		
	AO	2000-124197	04/28/2000	Japan (w/ English abstract and computer translation)	×	
	AP	1 081 749	07/03/2001	Europe (in English)		
	AQ	4-238882	08/1992	Japan (w/ certified English translation)	х	
	AR	1-312087	12/1989	Japan (w/ English abstract; corresponding to US Patent 4,968,374)		×
	AS	08-041309	02/1996	Japan (w/ English abstract and computer translation)	×	
	AT	08-081777	03/26/1996	Japan (w/ English abstract and computer translation)	x	
	AU	08-268751	10/15/1996	Japan (w/ English abstract and computer translation)	х	
	AV	07-226378	08/22/1995	Japan (w/ English abstract and computer translation)	×	
	AW	64-039728	02/1989	Japan (w/ certified English translation)	×	
	AX	03-115535	05/1991	Japan (w/ certified English translation)	×	
	AY	05-117064	05/1993	Japan (w/ English abstract and corresponding to EP 0 508 731 filed		×
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	AZ	05-238859	09/1993	Japan (w/ English abstract and computer translation)	×	
	BA		03/1994	Japan (w/ English abstract and computer translation)	×	
	ВВ		05/1994	Japan (w/ English abstract and computer translation)	<u> </u>	
	ВС	06-142822	05/1994	Japan (w/ English abstract and computer translation)	×	
	BD		05/1995	Japan (w/ English abstract and computer translation)	×	<u> </u>
	BE		07/1995	Japan (w/ English abstract and computer translation)	<u>×</u>	
	BF		02/1996	Japan (w/ English abstract and computer translation)	 	ļ
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	ВН		03/1997	Japan (w/ English abstract; corresponding to US Patent 5,909,354)	-	X
	BI	09-272987	10/1997	Japan (w/ English abstract; corresponding to US Patent 5,955,182)	<u> </u>	x
				Additional References sheet(s)	attached	
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Form PTO 14 COMMERCE	49	U.S. DEPA	RTMENT OF	ATTY DOCKET NO.	SERIAL	NO.
(Modified) OFFICE		PATENT	AND TRADEMARK	246070US2	10/722	,602
1.				APPLICANT		
LIST OF	REFERE	NCES CITED BY	APPLICANT	Kouji Mitsuhashi, et al.	GROUP	
				FILING DATE	1763	
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EXAMINE INITIAL	R	DOCUMENT NUMBER	DATE	COUNTRY	TRANSI YES	ATION NO
RD	AA	10-045461	02/1998	Japan (w/ English abstract and computer translation)	×	
	AB	10-045467	02/1998	Japan (w/ English abstract and computer translation)	×	
	AC	11-080925	03/1999	Japan (w/ English abstract; corresponding to US Patent 6,139,983)		×
	AD	11-207161	08/1999	Japan (w/ English abstract and computer translation)	×	
	AE	2001-031484	02/2001	Japan (w/ English abstract and computer translation)	×	
	AF	10-251871	09/1998	Japan (w/ English abstract; corresponding to US Patent 6,120,640)		×
	AG	02/48421	06/20/2002	WIPO (w/ English abstract; corresponding US 2004/0081746 A1)		×
	AH	01/42526	06/14/2001	WIPO (w/ English abstract; corresponding to US Patent 6,783,863)		×
	Al	0 508 731	10/14/1992	Europe (in English)		
	AJ	2001-164354	06/19/2001	Japan (w/ computer translation; English abstract; corresponding to US Patent 6,783,863)	×	
	AK	11-233292	08/27/1999	Japan (w/ English abstract and computer translation)	×	
	AL	11-312646	11/09/1999	Japan (w/ English abstract; corresponding to US Patent 6,383,333)		х
	AM	05-121360	05/18/1993	Japan (w/ English abstract and computer translation)	×	
	AN	94 21 671	07/1996	Germany (w/ computer translation)	x	
	AO	2 252 567	08/1992	Great Britain		
	AP	06-256926	09/1994	Japan (w/ English abstract and computer translation)	×	
	AQ	0 799 904	10/1997	Europe (in English)		
	AR	61-207566	09/1986	Japan (corresponding to US 5,204,189)		
	AS	07-058013 A	03/1995	Japan (English abstract and computer translation)	х	
	AT	02-267967	11/1990	Japan (Certified translation filed herewith)	×	
	AU	2004/030011	04/2004	WIPO		
	AV	2004/030012	04/2004	WIPO		
	AW	2004/030013	04/2004	WIPO		
	AX	2004/030014	04/2004	WIPO		
	AY	2004/030015	04/2004	WIPO		
	AZ	2004/030020	04/2004	WIPO		
	ВА	2004/030426	04/2004	WIPO		
	ВВ	2004/095530	11/2004	WIPO		
	ВС	2004/095532	11/2004	WIPO		
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				Additional References sheet(s)	attached	
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Form PTO 1449 COMMERCE		U.S. DEPAR		ATTY DOCKET NO.	SERIAL NO.		
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				APPLICANT			
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				FILING DATE	GROUP		
				November 28, 2003	1763		<u> </u>
			U.S. P.	ATENT DOCUMENTS			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	-	CLASS	SUB CLASS
RD	AA	6,176,969	01/23/2001	Park et al.			
	AB	5,919,332	07/06/1999	Koshiishi et al.			
	AC	2004/0035364	02/26/2004	Tomoyoshi et al.			
	AD	5,366,585	11-1994	Robertson et al.			
	AE	5,868,848	02-1999	Tsukamoto, Yuji			
	AF	6,110,287	08-2000	Arai et al.			
	AG	6,129,808	10-2000	Wicker et al.			
	АН	6,264,788	07-2001	Tomoyasu et al.			
	Al	6,394,026	05-2002	Wicker et al.			
	AJ	6,444,083	09-2002	Steger et al.			
	AK	6,514,377	02-2003	Morimoto, Tamotsu			
	AL	6,527,911	03-2003	Yen et al.			
	АМ	6,533,910	03-2003	O'Donnell et al.			
	AN	6,537,429	03-2003	O'Donnell et al.			
	AO	6,544,380	04-2003	Tomoyasu et al.			
	AP	6,583,064	06-2003	Wicker et al.			
	AQ	6,733,620	05-2001	Sugiyama et al.			
	AR	2002/0086501	07-2002	O'Donnell et al.			
	AS	2002/0086545	07-2002	O'Donnell et al.			
	AT	2002/0086553	07-2002	O'Donnell et al.			
	AU	2002/0142611	10-2002	O'Donnell et al.			
	AV	2003/0084848	05-2003	Long, Maolin			
	AW	2004/0026372	02-2004	Takenaka et al.			
	AX	2004/0060516	04-2004	Nishimoto et al.			
	AY	2004/0060656	04-2004	Saigusa et al.			
	AZ.	2004/0060657	04-2004	Saigusa et al.			
	ВА	2004/0060658	04-2004	Nishimoto et al.			
	вв	2004/0060661	04-2004	Nishimoto et al.		T	
	вс	2004/0061447	04-2004	Salgusa et al.			
	BD	2004/0063333	04-2004	Saigusa et al.			
	BE		07-2004	Ludviksson et al.			
	BF			· A	dditional References s	heet(s) attacl	hed
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Form PTO 14	40	U.S. DEPARTMENT	OF COMMERCE	ATTY DOCKET NO.		SERIAL N	NO.
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LIST	OF REFE	RENCES CITED BY A	PPLICANT	Kouji Mitsuhashi, et al.			
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			U.S	S. PATENT DOCUMENTS			
EXAMINE		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
RD	- AA	6,894,769	05/2005	Ludviksson et al.			
<u> </u>	AB	6,875,477	04/2005	Trickett et al.			
	AC	6,852,433	02/2005	Maeda, Takao			
	AD	6,833,279	12/2004	Choi, Jin-Sik			
	AE	6,811,651	11/2004	Long, Maolin			
	AF	6,806,949	10/2004	Ludviksson et al.			
	AG	6,805,952	10/2004	Chang et al.			
	AH	6,783,875	08/2004	Yamada et al.			
	Al	6,776,873	08/2004	Sun et al.			
	LA L	6,613,442	09/2003	O'Donnell et al.			
	AK	4,877,757	10/1989	York et al.			
	AL	5,637,237	06/1997	Oehrlein et al.			
	AM	5,834,070	11/1998	Movchan et al.			
	AN	6,296,740	10/2001	Xie et al.			
 -	AO	6,613,204	09/2003	Xie et al.			
	AP	5,891,253	04/1999	Wong et al.			····
	AQ	2004/0050495	03/2004	Sumiya et al.			
	AR	2004/0083970	05/2004	Imafuku et al.			
	AS	5,885,356	03/1999	Zhao et al.			
	AT	2001/0050144	12/2001	Nishikawa et al.			
	AU	5,902,763	05/1999	Waku et al.			
	AV	5,423,936	06/1995	Tomita et al.			
	AW	6,554,906	04/2003	Kuibira, et al.			
	AX	6,266,133	07/2001	Miyajima, et al.			
	AY	0,200,133	07/2001	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,			· · · · · · · · · · · · · · · · · · ·
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RD	AZ	Production drawing	g for Deposit	ion Shield, Upper believed to be	sold in t	he U.S. o	on April 12, 2000.
ſ		Production drawing	g for Deposit	tion Shield believed to be sold in	the U.S.	prior to	September 30,
	BA	2001.	•				
		Production drawing	g for Upper l	Electrode believed to be sold in the	he U.S. r	rior to S	eptember 30, 2001.
i	BB		B . C. OPP C		•		
	ВС	JIS Using Series, ' Association), with	Spraying Te	chniques Manual.", p. 95 (Oct. 3 slation	0, 1998,	Japanes	e Standard
···					Addi	tional Refe	rences sheet(s) attached
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			U.S	S. PATENT DOCUMENTS			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
RD	AA	4,842,683	06/1989	Cheng et al.			
1	AB	6,663,714	12/203	Mizuno et al.			
	AC	6,726,801	04/2004	Ahn, Jae-Su			
	AD	6,562,186	05-2003	Saito et al.	156	345.24	
	AE	5,885,402	03-1999	Esquibel, James	156	345.24	
	AF	2002/0177001	11-2002	Harada et al.	428	469	
	AG	5,521,790	05-1996	Ruckel et al.	361	234	
	AH	6,068,729	05-2000	Shrotriya, Ashish V.	156	345.26	
	Al	5,968,377	10-1999	Yuasa et al.			
	AJ	5,955,182	09/1999	Yasuda et al.			
	AK	6,364,949	4/2002	Or et al.			
	AL	5,911,852	6/1999	Katayama et al.			
	AM	5,074,456	12/1991	Degner et al.			
	AN	4,612,077	9/1986	Tracy et al.			
	AO	6,182,603	2/2001	Shang et al.			
 	AP	2003/0010446	1/2003	Kajiyama et al.			
	AQ	2001/0003271	6/2001	Otsuki			
	AR	2002/0076508	6/2002	Chiang et al.			
	AS	6,368,987	4/2002	Kopacz et al.			
	AT	2004/0072426	4/2004	Jung			
	AU	2005/0150866	07-2005	O'Donnell	216	067	· · · · · · · · · · · · · · · · · · ·
	AV	2003/0113479	06-2003	Fakuda et al.	427	569	
	AW	4,357,387	11-1982	George et al.	442	71	
	AX	5,925,228	07-1999	Panitz	204	484	
	AY	5,892,278	07-1999	Horita .	257	706	
	AZ	6,073,449	06-2000	Watanabe et al.	62	3.2	
	BA	2005/0103275	02-2004	Sasaki et al.			
	BB	4,310,390	01-1982	Bradley et al.			
7					Add	itional Refe	erences sheet(s) attached
Examiner	<u></u>	/R:	akesh Dhingr	ra/	Date Cor	sidered	08/08/2006
*Examiner: In	itial if r	eference is considered	I, whether or no	t citation is in conformance with MPEP with next communication to applicant.	609; Draw lii	ne through	citation if not in

conformance and not considered. Include copy of this form with next communication to applicant.

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			_	APPLICANT			
LIST OF	REFE	RENCES CITED BY APPL	LICANT	Kouji Mitsuhashi, et al.			
				FILING DATE		GROUP	
				November 28, 2003		1763	
			U.S	S. PATENT DOCUMENTS			
EXAMINER		DOCUMENT	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
INITIAL		NUMBER 5.	/2002	Nakahara et al.		00.00	
RD_	AA	-	/2000	Han et al.			
	AB		/2001	Schoepp et al.			
	AC	-	/2000	Kim et al.			
	· AD	0,000,000	1/1994	Rungta			
	AE	0,000,000		Ravi			
_	AF		/1999				
	AG	0,000,010	0/1997	Domfest et al.			
	AH		/1996	Ootuki			
	AJ	-	/1991	Wang et al.			
	AK	0,00 1,102	/1994	Vine et al.			
	AL		2/2004	O'Donnell et al.			
	AM		/2002	Luo et al.			
	AN		/2001	Walko, II			
	AO		/1999	Kholodenko			
	AP		/1997	Nitescu et al.			
	AQ	6,383,333 5/	/2002	Haino et al.			
	AR	6,590,660 7/	/2003	Jung et al.			
	AS	6,570,654 5/	/2003	Jung et al.			
	AT	6,519,037 2/	2003	Jung et al.			
	AU	6,373,573 4/	2002	Jung et al.			
	AV	6,246,479 6/	2001	Jung et al.			
	AW	5,851,343	2/1998	Hsu et al.			
	AX	6,210,486 4/	2001	Mizukami et al.			
	AY	2002/0086118 7/	2002	Chang et al.			
	ΑZ	2003/0029563 2/	2003	Kaushal et al.			
	ВА	4,593,007 6/	1986	Novinski			
	вв	5,985,102	1/1999	Leiphart			
	вс	6,106,625 8/	2000	Koal et al.			
	BD	6,123,804 9/	2000	Babassi et al.			
	BE	6,265,757 7/	2001	Brady et al.			
	BF	6,143,646	1/2000	Wetzel			
	BG	2002/0090464 7/	2002	Jiang et al.			
	вн	4,469,619 9/	1984	Ohno et al.			
	ВІ	5,426,310 6/	1995	Tamada et al.			
	ВЈ	5,556,501 9/	1996	Collins et al.			
	вк	5,614,055 3/	1997	Fairbairn et al.			
	BL	5,944,902 8/	1999	Redeker et al.	I	·	
	вм	5,994,662	1/1999	Murugesh			
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*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

SHEET 7 QF SERIAL NO. ATTY DOCKET NO. U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE Form PTO 1449 (Modified) 10/722,602 246070US2 APPLICANT LIST OF REFERENCES CITED BY APPLICANT Kouji Mitsuhashi, et al. **GROUP** FILING DATE 1763 November 28, 2003 **U.S. PATENT DOCUMENTS FILING DATE EXAMINER** DOCUMENT SUB CLASS NAME **CLASS** DATE IF APPROPRIATE INITIAL NUMBER 4/1999 Kelsey et al. AA 5,894,887 RD **b**/1999 Tepman et al. AΒ 5,879,575 5,759,360 6/1998 Ngan et al. AC 8/1998 Oehrlein et al. ΑD 5,798,016 Ohashi et al. 10/2000 ΑE 6,139,983 Waku et al. 1/1996 AF 5,484,752 4/1999 Kaji et al. 5,895,586 Shih et al. 9/2000 6,120,640 5/2004 Ross et al. 6,738,862 Αl ΑJ 6,783,863 8/2004 Harada et al. 6,837,966 1/2005 Nishimoto et al. ΑK 6,798,519 9/2004 Nishimoto et al. Nishimoto et al. AM 2004/0173155 9/2004 AN 6,641,697 11/2003 Han et al. 2004/0081746 4/2004 Imafuku AO 2003/0200929 10/2003 Otsuki AP 6,884,516 4/2005 Harada et al. AQ Kanekiyo et al. 6,695,929 2/2004 AR 5,725,960 3/1998 Konishi et al.. AS 5,551,190 Yamagishi et al. 9/1996 AT 5/2005 Nishimoto et al. 2005/0103268 ΑU 11/2004 Mitsuhashi et al. ΑV 2004/0216667 Additional References sheet(s) attached Date Considered Examiner /Rakesh Dhingra/ 08/08/2006 *Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.